



Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

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Schedule of Accreditation

[illegible]

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

Flexible scope in analytical tests: Type of matrix, analytes, experimental systems and/or analytical characteristics may be subject to changes, in accordance with the laboratory's approved and documented procedures. For details, please refer to the list of Accredited Tests, available from the laboratory upon request.

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The certificate attached is an integral part of the schedule and is numbered identically להספר הנספח



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Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Electrical Quantities - DC and LF						כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
21	A	T			(0 mV to 329.9999 mV]	8.4 μV/V		Fluke 8508A
22	A	T			(329.9999 mV to 3.299999 V]	15 μV/V		
23	A	T			(3.299999 V to 32.99999 V]	16 μV/V		
24	A	T			(32.99999 V to 329.999 V]	26 μV/V		
25	A	T			(329.9999 V to 1000 V]	26 μV/V		
26	A	P;T	DC Current. Sources	זרם ישר, מחוללים	0 μA	0.6 nA	MetCal	Datron 1281
27	A	P;T			(10 nA to 200 μA]	14.32 μA/A	Automated Calibration Software	Current clamp
28	A	P;T			(200 μA to 2 mA]	14.4 μA/A		Fluke 337
29	A	P;T			(2 mA to 20 mA]	1.49 μA/A		Fluke 5730A
30	A	P;T			(20 mA to 200 mA]	47.78 μA/A	Manufacturer instructions WI-C100	Fluke 8508A
31	A	P;T			(200 mA to 2 A]	2.15 μA/A		
32	A	P;T			(2 A to 20 A]	48.7 μA/A		
33	A	P;T	DC Current, Measuring Instruments	זרם ישר, מכשירי מדידת זרם	0 μA	0.007 μA	MetCal	
34	A	P;T			(2 nA to 220 μA]	120 μA/A	Automated Calibration Software	Standard resistors
35	A	P;T			(220 μA to 2.2 mA]	57 μA/A		Datron 1281
36	A	P;T			(2.2 mA to 22 mA]	52 μA/A		Wavetek 9100
37	A	P;T			(22 mA to 220 mA]	61 μA/A	WI-C100	Wavetek 4808
38	A	P;T			(220 mA to 2.2 A]	110 μA/A		Wavetek 4950
39	A	P;T			(2.2 A to 20 A]	480 μA/A		Fluke 5520A

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות. זהו חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח.



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Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks			
Calibration – Electrical Quantities - DC and LF						כיוול – גדלים חשמליים - זרם ישר ותדר נמוך					
40	A	P;T			(20 A to 105 A]	0.64 mA/A		Fluke 5725A			
41	A	P;T			(105 A to 160 A]	9.64 mA/A		Current Coils			
42	A	P;T			(160 A to 525 A]	32.2 mA/A		Fluke 5730A			
43	A	P;T			(525 A to 1000 A]	74.8 mA/A		Fluke 8508A			
44	A	P;T	AC Voltage, Sources	מתח חילופין מחוללים מתח	(0.2 mV to 200 mV]		MetCal Automated Calibration Software Manufacturer instructions WI-C100 WI-C106	Datron 1281			
					[1 Hz to 10 Hz]	127.5 μV/V			Wavetek 4950		
45	A	P;T			(20 Hz to 40 Hz]	125.3 μV/V			FLUKE 5730A		
46	A	P;T			(40 Hz to 100Hz]	124.9 μV/V			FLUKE 8508A		
47	A	P;T			(100Hz to 2 kHz]	124.7 μV/V					
48	A	P;T			(2 kHz to 10 kHz]	124.9 μV/V					
49	A	P;T			(10 kHz to 30 kHz]	131.7 μV/V					
50	A	P;T			(30 kHz to 100 kHz]	2.66 mV/V					
					(200 mV to 2 V]						
51	A	P;T			[1 Hz to 10 Hz]	162 μV/V					
52	A	P;T			(20 Hz to 40 Hz]	128.3 μV/V					
53	A	P;T						(40 Hz to 100Hz]	116.9 μV/V		
54	A	P;T						(100Hz to 2 kHz]	93.8 μV/V		
55	A	P;T			(2 kHz to 10 kHz]	116.6 μV/V					
56	A	P;T			(10 kHz to 30 kHz]	310.5 μV/V					

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Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Electrical Quantities - DC and LF					כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
57	A	P;T		(30 kHz to 100 kHz]	889.3 μ V/V		
58	A	P;T		(100 kHz to 300kHz]	889.3 μ V/V		
59	A	P;T		(300 kHz to 1MHz]	34.6 mV/V		
60	A	P;T		(2 V to 20V]	1.58 mV/V		
61	A	P;T		[1 Hz to 10 Hz]	1.57 mV/V		
62	A	P;T		(20 Hz to 40 Hz]	1.17 mV/V		
63	A	P;T		(40 Hz to 100Hz]	0.93 mV/V		
64	A	P;T		(100Hz to 2 kHz]	1.17 mV/V		
65	A	P;T		(2 kHz to 10 kHz]	2.77 mV/V		
66	A	P;T		(10 kHz to 30 kHz]	8.1 mV/V		
67	A	P;T		(30 kHz to 100 kHz]	57.8 mV/V		
68	A	P;T		(100 kHz to 300kHz]	346.47 mV/V		
69	A	P;T		(20V to 200V]	16 mV/V	MetCal	Datron 1281
70	A	P;T		[1 Hz to 10 Hz]	13.15 mV/V	Automated	Wavetek 4950
71	A	P;T		(20 Hz to 40 Hz]	12.1 mV/V	Calibration Software	FLUKE 5730A
72	A	P;T		(40 Hz to 100Hz]	10.8 mV/V	Manufacturer instructions	FLUKE 8508A
73	A	P;T		(100Hz to 2 kHz]	11.9 mV/V	WI-C100	
74	A	P;T		(2 kHz to 10 kHz]	11.9 mV/V	WI-C106	

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Calibration – Electrical Quantities - DC and LF						כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
75	A	P;T			(30 kHz to 100 kHz]	81 mV/V		
76	A	P;T			(100 kHz to 300kHz]	577.37 mV/V		
77	A	P;T			(300 kHz to 1MHz]	3465 mV/V		
					(200 V to 1050 V]			
78	A	P;T			[1 Hz to 40 Hz]	141 mV/V		
79	A	P;T			(40 Hz to 10kHz]	73.4 mV/V		
80	A	P;T			(10kHz to 30 kHz]	162 mV/V		
81	A	P;T			(30 kHz to 100 kHz]	520 mV/V		
82	A	P;T	AC Voltage. Measuring Instruments	מתח חילופין מכשירי מדידת מתח	(0.2 mV to 220 mV]		MetCal Automated Calibration Software Manufacturer instructions WI-C100 WI-C102 WI-C105	Datron 1281 Wavetek 9100 Wavetek 4808 Wavetek 4950 Fluke 5520A FLUKE 5730A FLUKE 8508A
83	A	P;T			(10Hz to 20 Hz]	431 μV/V		
84	A	P;T			(20 Hz to 40 Hz]	204 μV/V		
85	A	P;T			(40 Hz to 20 kHz]	162 μV/V		
86	A	P;T			(20 kHz to 50 kHz]	230 μV/V		
87	A	P;T			(50 kHz to 100 kHz]	566 μV/V		
					(100 kHz to 300 kHz]	1.1 mV/V		

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Calibration – Electrical Quantities - DC and LF					כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
88	A	P;T		(300 kHz to 500 kHz]	2.0 mV/V		
89	A	P;T		(500 kHz to 1 MHz]	3.9 mV/V		
90	A	P;T		(220 mV to 2.2 V]			
91	A	P;T		(10Hz to 20 Hz]	325 μ V/V		
92	A	P;T		(20 Hz to 40 Hz]	134 μ V/V		
93	A	P;T		(40 Hz to 20 kHz]	62 μ V/V		
94	A	P;T		(20 kHz to 50 kHz]	93 μ V/V		
95	A	P;T		(50 kHz to 100 kHz]	136 μ V/V		
96	A	P;T		(100 kHz to 300 kHz]	489 μ V/V		
97	A	P;T		(300 kHz to 500 kHz]	1.5 mV/V		
98	A	P;T		(500 kHz to 1 MHz]	2.7 mV/V	MetCal	
99	A	P;T		(2.2 V to 22 V]		Automated Calibration Software	
100	A	P;T		(10Hz to 20 Hz]	331 μ V/V	Manufacturer instructions	
101	A	P;T		(20 Hz to 40 Hz]	128 μ V/V	WI-C100	
102	A	P;T		(40 Hz to 20 kHz]	60 μ V/V	WI-C102	
103	A	P;T		(20 kHz to 50 kHz]	95 μ V/V	WI-C105	
104	A	P;T		(50 kHz to 100 kHz]	132 μ V/V		

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Calibration – Electrical Quantities - DC and LF						כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
103	A	P;T			(100 kHz to 300 kHz]	430 μV/V		
104	A	P;T			(300 kHz to 500 kHz]	1.5 mV/V		
105	A	P;T			(500 kHz to 1 MHz]	2.7 mV/V		
					(22 V to 220 V]			
106	A	P;T			(10Hz to 20 Hz]	299 μV/V		
107	A	P;T			(20 Hz to 40 Hz]	122 μV/V		
108	A	P;T			(40 Hz to 20 kHz]	81 μV/V		
109	A	P;T			(20 kHz to 50 kHz]	105 μV/V		
110	A	P;T			(50 kHz to 100 kHz]	187 μV/V		
111	A	P;T			(100 kHz to 300 kHz]	1.1 mV/V		
112	A	P;T			(300 kHz to 500 kHz]	5.1 mV/V		
113	A	P;T			(500 kHz to 1 MHz]	9.3 mV/V		
					(220 V to 1100 V]			
114	A	P;T			(15 Hz to 50 Hz]	348 μV/V		
115	A	P;T			(50 Hz to 1kHz]	84 μV/V	Manufacturer instructions WI-C100	
116	A	P;T	AC Current Sources	זרם חילופין מחוללי זרם	(200 μA to 2 mA] [1 Hz to 10 Hz]	524 μA/A	MetcalAutomated Calibration Software Manufacturer Instruction WI-C100	Datron 1281 Wavetek 4950 Fluke 337

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Calibration – Electrical Quantities - DC and LF						כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
117	A	P;T			[10 Hz to 10 kHz]	523 μA/A		Fluke 5780A
118	A	P;T			(10 kHz to 30 kHz]	929 μA/A		Fluke 5725A
119	A	P;T			(30 kHz to 100 kHz]	0.93 mA/A		Fluke 8508A
					(2 mA to 20 mA]			
120	A	P;T			*[1 Hz to 10 Hz]	521 μA/A		
121	A	P;T			[10 Hz to 10 kHz]	521 μA/A		
122	A	P;T			(10 kHz to 30 kHz]	925 μA/A		
123	A	P;T			(30 kHz to 100 kHz]	4.85 mA/A		
					(20 mA to 200 mA]			
124	A	P;T			[1 Hz to 10 Hz]	26.64 μA/A		
125	A	P;T	[10 Hz to 10 kHz]	522 μA/A				
126	A	P;T	(10 kHz to 30 kHz]	925 μA/A				
			(200 mA to 2 A]					
127	A	P;T	(10 Hz to 2 kHz]	925 μA/A				
128	A	P;T	(2 kHz to 10 kHz]	1040 μA/A				

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

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Calibration – Electrical Quantities - DC and LF						כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
129	A	P;T			(10 kHz to 30 kHz] (2 A to 20 A]	3.71 mA/A		
130	A	P;T			(10 Hz to 2 kHz]	1.2 mA/A		
131	A	P;T			(2kHz to 10kHz]	3.2mA/A		
132	A	P;T	AC Current Measuring Instruments	זרם חילופין מכשירי מדידה	(0.1 μA to 220 μA]		MetCal	Datron 1281
133	A	P;T			[10 Hz to 20Hz]	487 μA/A	MTS Automated Calibration Software	Wavetek 9100 Wavetek 4808 Wavetek MTS 4950
134	A	P;T			[20 Hz to 40Hz]	314 μA/A	Manufacturer instructions	Fluke 5520A Fluke 5720A
135	A	P;T			[40 Hz to 1 kHz]	223 μA/A	WI-C100	Current Coils
136	A	P;T			[1 kHz to 5 kHz]	525 μA/A	WI-C102	
137	A	P;T			(5 kHz to 10 kHz]	2.2 mA/A		
					(220 μA to 2.2 mA]			
					[10 Hz to 20Hz]	347 μA/A		
138	A	P;T			[20 Hz to 40Hz]	238 μA/A		
139	A	P			[40 Hz to 1 kHz]	170 μA/A		
140	A	P;T	[1 kHz to 5 kHz]	340 μA/A				
141	A	P	(5 kHz to 10 kHz]	2.1 mA/A				

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Calibration – Electrical Quantities - DC and LF						כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
142 A	P;T				(2.2 mA to 22 mA]			
					[10 Hz to 20Hz]	363 μA/A		
143 A	P;T				[20 Hz to 40Hz]	245 μA/A		
144 A	P;T				[40 Hz to 1 kHz]	178 μA/A		
145 A	P;T				[1 kHz to 5 kHz]	365 μA/A		
146 A	P;T				(5 kHz to 10 kHz]	1.95 mA/A		
					(22 mA to 220 mA]			
147 A	P;T				[10 Hz to 20Hz]	360 μA/A		
148 A	P;T				[20 Hz to 40Hz]	243 μA/A		
149 A	P;T				[40 Hz to 1 kHz]	171 μA/A		
150 A	P;T				[1 kHz to 5 kHz]	321 μA/A		
151 A	P;T				(5 kHz to 10 kHz]	1.6 mA/A		
		(220 mA to 2.2 A]						
152 A	P;T	[20 Hz to 1 kHz]	344 μA/A					
153 A	P;T	(1 kHz to 5 kHz]	674 μA/A					
154 A		(5 kHz to 10 kHz]	8.4 mA/A					
155 A	P;T	(2.2 A to 11 A]						
		(40 Hz to 1 kHz]	558 μA/A					

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Calibration – Electrical Quantities - DC and LF						כיוול – גדלים חשמליים - זרם ישר ותדר נמוך			
156	A	P;T			(1 kHz to 5 kHz]	1.2 mA/A			
157	A	P;T			(5 kHz to 10 kHz]	4.3 mA/A			
158	A	P;T			(11 A to 20.5 A]	(45 Hz to 100 Hz]			7.23 mA/A
159	A	P;T			(100Hz to 1 kHz]	7.6 mA/A			
160	A	P;T			(1 kHz to 5 kHz]	41 mA/A			
161	A	P;T			(20 A to 32 A]	8.2 mA/A			
162	A	P;T			(10 Hz to 440 Hz]	39 mA/A			
					(32 A to 160 A]				
163	A	P;T			(160 A to 200 A]	68 mA/A			
					(10 Hz to 440 Hz]				
164	A	P;T	(200 A to 1000 A]	195 mA/A					
165	A	P;T	DC Resistance, Resistors Shunts	התנגדות זרם ישר, נגדים מיצד זרם	0.0001 Ω	160 mΩ/Ω	Manufacturer instructions WI-C100 WI-C101 WI-C103	DMM 1281A DMM 34401A FLUKE 8508A DMM 6.5digit	
166	A	P;T			0.0002 Ω	79 mΩ/Ω			
167	A	P;T			0.0005 Ω	31 mΩ/Ω			
168	A	P;T			0.005 Ω	310 μΩ/Ω			
169	A	P;T			0.001 Ω	1.54 mΩ/Ω			
170	A	P;T			0.01 Ω	1.5 mΩ/Ω			
171	A	P;T			0.1 Ω	2.3 mΩ/Ω			
172	A	P;T			0 Ω	5 μΩ			

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Electrical Quantities - DC and LF						כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
173	A	P;T			1 Ω	1.6 mΩ/Ω		
174	A	P;T			1.9 Ω	1.41 mΩ/Ω		
175	A	P;T			10 Ω	1 mΩ/Ω		
176	A	P;T			19 Ω	0.9 mΩ/Ω		
177	A	P;T			50 Ω	952 μΩ/Ω		
178	A	P;T			100 Ω	910 μΩ/Ω		
179	A	P;T			190 Ω	870 μΩ/Ω		
180	A	P;T			1 kΩ	9.01 μΩ/Ω		
181	A	P;T			1.9 kΩ	17 μΩ/Ω		
182	A	P;T			10 kΩ	89.4 μΩ/Ω		
183	A	P;T			50 kΩ	168.9 μΩ/Ω		
184	A	P;T			100 kΩ	0.92 mΩ/Ω	Manufacturer instructions WI-C100 WI-C101 WI-C103	
185	A	P;T			190 kΩ	1.69 mΩ/Ω		
186	A	P;T			1 MΩ	10.9 μΩ/Ω		
187		P,T			1.9 MΩ	19 μΩ/Ω		

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Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

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Calibration – Electrical Quantities - DC and LF						כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
188	A	P;T			10 MΩ	251 μΩ/Ω		
189	A	P;T			19 MΩ	351 μΩ/Ω		
190	A	P;T			100 MΩ	4.65 mΩ/Ω		
191	A	P;T			1 GΩ	317 μΩ/Ω		
192	A	P;T			[High Amp. Std. Shunt] 0.0005Ω÷0.5 Ω @ 141A	0.016%	Manufacturer instructions WI-C101	
193	A	P;T			0.0005Ω÷0.5 Ω @ 224A	0.016%		
194		P,T			0.0005Ω÷0.5 Ω @ 300A	0.016%		
195	A	P;T			0.0001Ω÷0.5 Ω @ 10A÷300A	0.11%		

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Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Electrical Quantities - DC and LF						כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
196	A	P;T	DC Resistance, Sources	התנגדות זרם ישר, מחוללים	(0 Ω to 2 G Ω]	17 μΩ/Ω + 4μΩ	MetCal Automated Calibration Software Manufacturer instructions WI-C100 WI-C101 WI-C103	Wavetek 9100 Fluke 5522A Datron 1281 Wavetek 4808 Standard resistance Wavetek 4950 FLUKE 5730A FLUKE 8508A
197	A	P;T			(0 Ω to 2 Ω]			
198	A	P;T			(2 Ω to 20 Ω]			
199	A	P;T			(20 Ω to 200 Ω]			
200	A	P;T			(200 Ω to 2 kΩ]			
201	A	P;T			(2 kΩ to 20 kΩ]			
202	A	P;T			(20 kΩ to 200 kΩ]			
203	A	P;T			(200 kΩ to 2 MΩ]			
204	A	P;T			(2 MΩ to 20 MΩ]			
205	A	P;T			(20 MΩ to 200 MΩ]			
206	A	P;T			(200 MΩ to 2 GΩ]			
					(2 GΩ to 100 GΩ]	0.18%		
207	A	P;T	DC Resistance, Measuring Instruments	התנגדות זרם ישר, מכשירי מדידה	(1 μΩ to 10 Ω]	21 μΩ/Ω	MetCal Automated Calibration Software Manufacturer instructions WI-C100 WI-C101	Wavetek 4950 Datron 1281 Wavetek 9100 QCC 23-135
208	A	P;T			(10 Ω to 100 Ω]			
209	A	P;T			(100 Ω to 10 kΩ]			
210	A	P;T			(10 kΩ to 100 kΩ]			
211	A	P;T			(100 kΩ to 1 MΩ]			
212	A	P;T			(1 MΩ to 10 MΩ]			
213	A	P;T			(10 MΩ to 100 MΩ]			
214	A	P;T			(100 MΩ to 1 GΩ]			
215	A	P;T			(10 GΩ to 100 GΩ]	8.4 mΩ/Ω		

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Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks		
Calibration – Electrical Quantities - DC and LF						כיוול – גדלים חשמליים - זרם ישר ותדר נמוך				
216	A	P;T	Std Resistors, MFC source Measuring Instruments	נגדים סטנדרטיים כיילים רב-תחומיים מכשירי מדידה	1 Ω	7 μΩ/Ω	Manufacturer instructions			
217	A	P;T			1.9 Ω	111 μΩ/Ω	WI-C100			
218	A	P;T			10 Ω	8 μΩ/Ω	WI-C101			
219	A	P;T			19 Ω	27 μΩ/Ω				
220	A	P;T			100 Ω	8 μΩ/Ω				
221	A	P;T			190 Ω	12 μΩ/Ω				
222	A	P;T			1 kΩ	8 μΩ/Ω				
223	A	P;T			1.9 kΩ	8 μΩ/Ω				
224	A	P;T			10 kΩ	3.5 μΩ/Ω				
225	A	P;T			19 kΩ	8 μΩ/Ω				
226	A	P;T			100 kΩ	13 μΩ/Ω				
227	A	P;T			190 kΩ	11 μΩ/Ω				
228	A	P;T			1 MΩ	16 μΩ/Ω				
229	A	P;T			1.9 MΩ	23 μΩ/Ω				
230	A	P;T			10 MΩ	47 μΩ/Ω				
231	A	P;T			19 MΩ	57 μΩ/Ω				
					Capacitance, Measuring Instruments	קיבול מכשירי מדידה	(0.5 nF to 4 nF] Up to 350 Hz]			MetCal Automated

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Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Electrical Quantities - DC and LF					כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
232	A	P;T				Calibration Software	GR Capacitance Decade
233	A	P;T		(350 Hz to 1.5 kHz] (4 nF to 40 nF]	2.5 mF/F	Manufacturer instructions WI-C100	Standard Capacitors FLUKE 5502E FLUKE 5522A
234	A	P;T		Up to 350 Hz]	4.2 mF/F		
235	A	P;T		(350 Hz to 1.5 kHz] (40 nF to 400 nF]	4.2 mF/F		
236	A	P;T		Up to 350 Hz]	15.6 mF/F		
237	A	P;T		(350 Hz to 1.5 kHz] (400 nF to 4 μF]	15.66 mF/F		
238	A	P;T		Up to 350 Hz]	1.2 mF/F		
239	A	P;T		(350 Hz to 1.5 kHz] (4 μF to 40 μF]	1.2 mF/F		
240	A	P;T		Up to 350 Hz]	769 μF/F		
241	A	P;T		(350 Hz to 1.5 kHz] (40 μF to 400 μF]	769 μF/F		
242	A	P;T		Up to 350 Hz]	501 μF/F		
243	A	P;T		(350 Hz to 1.5 kHz] (400 μF to 4 mF]	501 μF/F		
244	A	P;T		Up to 350 Hz]	1.2 mF/F		
245	A	P;T		(350 Hz to 1.5 kHz]	1.2 mF/F		
				(4 mF to 40 mF]		Manufacturer instructions	

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות

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Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks	
Calibration – Electrical Quantities - DC and LF						כיוול – גדלים חשמליים - זרם ישר ותדר נמוך			
246	A	P;T			Up to 350 Hz]	1.2 mF/F	WI-C100		
247	A	P;T			(350 Hz to 1.5 kHz]	1.2 mF/F			
248	A	P;T	Capacitance, Capacitors	קיבול, קבלים	0.001 μF	6 mF/F	Manufacturer instructions WI-C100		
		1000 Hz							
		0.005 μF							
249	A	P,T			1000 Hz				262 μF/F
250	A	P,T			1000 Hz				595 μF/F
251	A	P,T			1000 Hz				137 μF/F
252	A	P,T			0.1 μF				
					1000 Hz	92 μF/F			
253	A	P	Phase angle, Measurement Phase angle meters	זווית מופע מכשירי מדידה מדי זווית מופע	(0° to 90°) Frequency: [45 Hz to 65 Hz]	0.58°	Manufacturer Instructions WI-C108	FLUKE 5520A FLUKE 5522A Electrical test Equipment CALIBRATOR	
254		P			Frequency: [65 Hz to 500 Hz] Parameters: V: 32 mV to 600 V I: 32 mA to 20 A Alternating V: 10 mV to 5 V When current transducer not allowed	0.21°	Manufacturer instructions WI-C108		

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Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Electrical Quantities - DC and LF						כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
255	A	P,T	AC Power, Measurement Power Meters	הספק מתח חילופין מדי הספק	[1mW to 20 kW] Power factor: [0– 1] Frequency: [45 Hz to 65Hz]	3.5 %	MetCal Automated Calibration Software	Fluke 5520A Fluke 5522A Electrical Test Equipment calibrator
256	A	P,T	Power factor, Measurement Power Meters	מקדם הספק מדידה מדי הספק	[0– 1] Power: [1mW to 20 kW] Frequency: [45 Hz to 65Hz]	0.14	Manufacturer instruction WI-C108	
257	A	P,T	DC Power, Measurement Power Meters	הספק מתח ישר מדי הספק	[10 mW to 20 kW]	0.5 %		
258	A	P,T	Continuity resistance Resistance, measuring instruments	התנגדות רציפות, מכשירי מדידת התנגדות	0.20 Ω to 20 Ω	1.5%	MetCal Automated Calibration Software	TRANSMILLE 3200 Electrical Test Equipment Calibrator
259	A	P,T			20 Ω to 200 Ω	1.2%		
260	A	P,T			200 Ω to 2 kΩ	1.2%	Manufacturer instructions	
261	A	P,T	Continuity current Current measuring instruments	זרם רציפות מכשירי מדידת זרם	(0 mA to 320 mA]	4%	WI-C107	
262	A	P,T	Insulation resistance Resistance, measuring instruments	התנגדות של בידוד מכשירי מדידת התנגדות	0.01MΩ to 5.00 MΩ	3.2%	MetCal Automated Calibration Software	TRANSMILLE 3200 Electrical Test Equipment Calibrator
263	A	P,T			5 MΩ to 2 GΩ	3.6%	Manufacturer instructions WI-C107	
264	A	P,T			2 G Ω to 10 GΩ	5.8%		
265	A	P,T			10 GΩ to 1 TΩ	5.8%		

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Calibration – Electrical Quantities - DC and LF						כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
266	A	P,T	Residual current AC Residual Current, Sensing Devices (RCD)	זרם חילופין שיורי (מכשירי חישת RCD)	(Up to 5 Sec.] 3.00 mA to 10.00 mA	2 mA/A	MetCal Automated Calibration Software	TRANSMILLE 3200 Electrical Test Equipment Calibrator
267	A	P,T			10.1 mA to 100 mA	1.39 mA/A	Manufacturer instructions WI-C107	
268	A	P,T			101 mA to 1 A	7.81 mA/A		
269	A	P,T			1.01 A to 3 A	34.8 mA/A		
270	A	P,T			(< 190 m Sec.] 3 mA to 10mA	6 mA/A		
271	A	P,T			10.1 mA to 100 mA	6.5 mA/A		
272	A	P,T			101 mA to 1 A	5 mA/A		
273	A	P,T			1.01 A to 3A	5.6 mA/A		
274	A	P,T	Residual current duration AC Loop Resistance Loop Testing Devices.	התנגדות לולאה בזרם חילופין מכשירי בדיקת לולאה	0.05 Ω	0.0075 Ω	Manufacturer instructions WI-C107	
275	A	P,T			0.1 Ω	0.0079 Ω		
276	A	P,T			0.22 Ω	0.0087 Ω		
277	A	P,T			0.33 Ω	0.0097 Ω		
278	A	P,T			0.5 Ω	0.011 Ω		
279	A	P,T						

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Calibration – Electrical Quantities - DC and LF					כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
280	A	P,T			1 Ω	0.017 Ω	
281	A	P,T			5 Ω	0.067 Ω	
282	A	P,T			10 Ω	0.13 Ω	
283	A	P,T			100 Ω	1.3 Ω	
					1 k Ω	13 Ω	
284	A	P,T	Auto Loop Resistance AC Auto Loop Resistance. Loop Testing devices.	התנגדות לולאה בזרם AC מכשירי בדיקת לולאה.	1 Ω	0.06Ω	MetCal Automated Calibration Software Manufacturer instructions WI-C107 TRANSMILLE 3200 Electrical Test Equipment Calibrator
285	A	P,T	Earth Bond Resistance	התנגדות בדיקת חיבור להארקה מכשירי PAT	0.05 Ω	0.0049 Ω	
286	A	P,T	Bond Resistance		0.1 Ω	0.0053 Ω	
287	A	P,T	PAT (Portable Appliance Tester)		0.22 Ω	0.0059 Ω	
288	A	P,T			0.33 Ω	0.0065 Ω	
289	A	P,T			0.5 Ω	0.0076 Ω	
290	A	P,T			1 Ω	0.010 Ω	
291	A	P,T			5 Ω	0.033 Ω	
292	A	P,T			10 Ω	0.062 Ω	
293	A	P,T			100 Ω	0.582 Ω	
294	A	P,T			1 k Ω	5.77 Ω	
295	A	P,T	Earth Bond Current Bond current,	זרם בדיקת חיבור להארקה	100.0 mA	9.3 mA	
296	A	P,T	PAT (Portable Appliance Tester)	מכשירי PAT	10.00 A	0.24 A	
297	A	P,T			30.00 A	0.59 A	
298	A	P,T	Insulation Resistance	התנגדות בידוד,	0 MΩ	0.0074 MΩ	

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Calibration – Electrical Quantities - DC and LF						כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
299	A	P,T	Resistance, PAT (Portable Appliance Tester)	מכשירי PAT	0.01 MΩ to 5 MΩ	3 %		
300	A	P,T			5MΩ to 2 GΩ	3.5 %		
301	A	P,T	Leakage Current, PAT (Portable Appliance Tester)	זליגת זרם להארקה מכשירי PAT	2.000 mA	0.038 mA	MetCal Automated Calibration Software Manufacturer instructions	TRANSMILLE 3200 Electrical Test Equipment Calibrator
302	A	P,T			4.700 mA	0.084 mA		
303	A	P,T			7.700 mA	0.136 mA		
304	A	P,T	Flash Voltage PAT (Portable Appliance Tester)	מתח פריצת בידוד מכשירי PAT	Class 1 (1.5 kV) (1 kV to 1.8 kV]		WI-C107 WI-C100	
					1000 V	57 V		
305	A	P,T			1500 V	81 V		
306	A	P,T			Class 2 (3 kV) (2 kV to 3 kV]			
					3000 V	151 V		
307	A	P,T	Flash Current PAT (Portable Appliance Tester)	זרם פריצת בידוד מכשירי PAT	(1 mA to 3 mA] 1.00 mA	0.06 mA		
308	A	P,T	Line Voltage Measurement of line voltage	מתח רשת חשמל, מדידת מתח רשת חשמל	(200 V (rms)) to 260 V(rms)]	1.2 %		
309	A	P,T	Breakdown/Hipot Measurement of high voltage	מדידת מתח גבוה	(3 kV AC @ 50 Hz) 1.00 kV 2.00 kV 3.00 kV (12 kV AC @ 50 Hz)	0.05 kV	Manufacturer instructions WI-C107	
310	A	P,T				0.06 kV		
311	A	P,T				0.06 kV		
312	A	P,T						

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

Flexible scope in analytical tests: Type of matrix, analytes, experimental systems and/or analytical characteristics may be subject to changes, in accordance with the laboratory's approved and documented procedures. For details, please refer to the list of Accredited Tests, available from the laboratory upon request.

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The certificate attached is an integral part of the schedule and is numbered identically להספר הנספח

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks			
Calibration – Electrical Quantities - DC and LF						כיוול – גדלים חשמליים - זרם ישר ותדר נמוך					
313	A	P,T			4.00 kV	0.07 kV					
314	A	P,T			6.00 kV	0.08 kV					
315	A	P,T			8.00 kV	0.10 kV					
316	A	P,T			10.00 kV	0.11 kV					
317	A	P,T			(25 kV AC @ 50 Hz)						
					12 kV to 25 kV	1.2% O.R.					
318	A	P,T			3 kV DC						
319	A	P,T			1.00 kV	0.05 kV					
320	A	P,T			2.00 kV	0.06 kV					
					3.00 kV	0.06 kV					
321	A	P,T			(12 kV DC)		Manufacturer instructions WI-C107	HV Probe 80K-40 DMM TRANSMILLE 3200			
	322	A			P,T	4.00 kV			0.07 kV		
	323	A			P,T	6.00 kV			0.08 kV		
	324	A			P,T	8.00 kV			0.09 kV		
	325	A			P,T	10.00 kV			0.10 kV		
					12.00 kV	0.12 kV					
326	A	P,T			(40 kV DC)						
					12 kV to 40 kV	1.0% O.R.					

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks	
Calibration – Electrical Quantities - DC and LF					כיוול – גדלים חשמליים - זרם ישר ותדר נמוך			
327	A	P,T	Measurement of current at high voltage	מדידת זרם במתח גבוה	1 kV AC @ 50 Hz	Manufacturer instructions WI-C107		
328	A	P,T			200 µA			1.7 µA
329	A	P,T			2.00 mA			0.04 mA
330	A	P,T			20.00 mA			0.16 mA
331	A	P,T			1 kV DC			
332	A	P,T			200 µA			1.7 µA
333	A	P,T			2.00 mA			0.04 mA
334	A	P,T	DC High Voltage, Source	מחוללי מתח גבוה ישר	40 kV DC)	Manufacturer instructions WI-C107	SPELLMAN SL40P2000 HV Probe 80K-40 DMM	
					1 kV to 40 kV			2.4% O.R.

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח



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Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Electrical Quantities - RF Frequency, Time					כיוול – גדלים חשמליים - תדר גבוה, זמן		
335	A	P	Frequency, Sources תדר, מחוללי תדר	[0.037 Hz to 10 MHz]	10^{-11} (24 h)	MetCal WI-C102 WI-C105 WI-C106	FLUKE 910R Wavetek 9500 H.P.5248 M H.P. 53132 A Via GPS System With Ref. Locked to 910R
336	A	P		[10 MHz to 3.2 GHz]	5×10^{-9} (0.3 h)	MetCal WI-C102 WI-C105 WI-C106	FLUKE 910R Wavetek 9500 H.P.5248 M H.P. 53132 A Via GPS System With Ref. Locked to 910R (with 9500 + 9530)
337	A	T		[10 MHz to 3.2 GHz]	4.8×10^{-5} (0.3 h)	MetCal WI-C102 WI-C105 WI-C106	Wavetek 9500 H.P.5248 M H.P. 53132 A With Internal Reference
338	A	P	Frequency. Counters תדר, מוני תדר	[0.1 Hz to 100 MHz]	4.8×10^{-9} (0.3 h)	WI-C102 WI-C105 WI-C106	With Ref. Locked to 910R
339	A	P		[100 MHz to 3 GHz]	4.8×10^{-10} (0.3 h)		With Ref. Locked to 910R (with 9500 + 9530)
340	A	T		[0.1 Hz to 3 GHz]	1.4×10^{-5} (0.3 h)		With Internal Reference
341	A	P;T	Timers, stopwatches שעוני עצר, מוני זמן	[1 sec to 24 hr]	0.1 sec	Manufacturer instructions WI-C070	השוואה למדיד אב

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות

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Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Electrical Quantities - RF Frequency, Time						כיוול – גדלים חשמליים - תדר גבוה, זמן		
342	A	P;T	Oscilloscope Time markers function: Square wave, Pulse, Narrow Triangle	ציר אופקי במשקף תנודות	[0.45 ns to 55 sec]	0.038 μs/s	Software MetCal Software WI-C102	Wavetek 9500 Fluke 910R External reference input in the range 1 MHz to 20 MHz
343	A	P;T	Oscilloscope Amplitude Square Wave	ציר אנכי במשקף תנודות	Input impedance 1 MΩ Peak to peak amplitude (40 μV to 1 mV]	10 mV/V + 10 μV	MetCal Software WI-C102 WI-C105 WI-C106	Wavetek 9500 Fluke 910R External reference input in the range 1 MHz to 20 MHz
344	A	P;T			(1 mV to 200 V]	1 mV/V + 10 μV		
345	A	P;T	Oscilloscope Amplitude Square Wave	ציר אנכי במשקף תנודות	Input impedance 50 Ω Peak to peak amplitude (40 μV to 1 mV pk-pk]	10 mV/V + 10 μV	MetCal Software WI-C102 WI-C105 WI-C106	Wavetek 9500
346	A	P;T			(1 mV to 5 V pk-pk]	1 mV/V + 10 μV		
347	A	P;T	Oscilloscope Rise Time	זמן עליית האות של משקף תנודות	Rise time, From 150 ps]	14 ps	MetCal Software WI-C102 WI-C105 WI-C106	Wavetek 9500
348	A	P;T	Oscilloscope Bandwidth:	רוחב סרט של משקף תנודות	[0.1 Hz to 300 MHz]	0.23 db	MetCal Software WI-C102 WI-C105 WI-C106	Wavetek 9500
349	A	P;T			[300 MHz to 550 MHz]	0.23 db		
350	A	P;T			[550 MHz to 1.1GHz]	0.29 db		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Electrical Quantities - RF Frequency, Time						כיוול – גדלים חשמליים - תדר גבוה, זמן		
351	A	P;T			[1.1 GHz to 3.2 GHz]	0.36 db		
352	A	P;T	Oscilloscope Flatness	מישוריות האות כתלות בתדר ביחס לתדר הייחוס	[0.1 Hz to 300 MHz]	2.3 %	MetCal Software WI-C102 WI-C105 WI-C106	Wavetek 9500 Leveled Sine Wave Amplitude 50 kHz Ref
353	A	P;T			[300 MHz to 550 MHz]	3.8 %		
354	A	P;T			[550 MHz to 1.1 GHz]	4.9 %		
355	A	P;T			[1.1 GHz to 3.2 GHz]	6.0 %		
356	A	P;T	Oscilloscope Input Capacitance	קיבול כניסה של משקף תנודות	[1 pF to 65 pF]	7 mF/F	MetCal Software WI-C102 WI-C100	Wavetek 9500 Input impedance 50 Ω

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities - Form, Angle						כיוול – גדלים מכניים - צורה, זווית		
357	A	P	Flank Angle Screw Plug Gauges (parallel) including check and setting Plug	זווית השן מדיד הברגה זכר מקביל	Plug Diameter [1 mm to 305 mm]	[2+(800/M×P)] Minutes of arc	WI-C020	M is projector magnification and P is pitch in mm
358	A	P	Flank angle Screw Plug Gauges (taper)	זווית השן מדיד הברגה זכר קוני	Plug Diameter [1 mm to 305 mm]	[2+(800/M×P)] Minutes of arc	WI-C020	M is projector magnification and P is pitch in mm
359	A	P	Flatness of Optical Flats in diameter of 10 mm – 50 mm	מישוריות של משטחים אופטיים בעלי קוטר 10 – 50 mm	Above 0.05 μm	0.1 μm	FED-GG-0-635 JIS B 7430 JIS B 7431	Optical flat/parallel מערכת כיוול מקבילונים ועדשה מישורית The uncertainty quoted is for the departure from flatness of parallelism, i.e. the distance separating the two parallel planes, which just enclose by
360	A	P	Parallelism of Optical Parallels in diameter of 10 mm – 50 mm	מקבילות של משטחים אופטיים בעלי קוטר 10 – 50 mm	Above 0.01 μm	0.1 μm	WI-C009	The uncertainty quoted is for the departure from flatness of parallelism, i.e. the distance separating the two parallel planes, which just enclose by

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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The certificate attached is an integral part of the schedule and is numbered identically להספד הנספח

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities - Form, Angle						כיוול – גדלים מכניים - צורה, זווית		
361	A	P;T	Flatness of Granites or Cast iron surfaces in Grade 00	מישורית של לוחות משטח גרניט וברזל יציקה ברמה 00	Above 0.1 µm	[1.5+0.8* length] µm	DIN 876 P1,2 ISO 8152 P1,2 GGG-P-463-C	עד 0.09 m² נבדק באמצעות גשש אורך. מעל 0.09 m² נבדק במערכת פלסים אלקטרוניים. The uncertainty quoted is for the departure from flatness, straightness, parallelism, or squareness i.e. the distance separating the two parallel planes which, just enclose the surface under consideration (Length in m)
362	A	P	Straightness, flatness and parallelism of Granite, Cast iron and Steel straightedges in Grade 00	ישרות, מישוריות, מקבילות של סרגל ישרות מתכת או גרניט ברמה 00	Above 1 µm	4.3 µm	DIN 874 P.1	גששי אורך
363	A	P	Straightness Knife edge, straight edge	סרגל שערה	Up to 500 mm]	1.5 µm	DIN 874 P.2	מקור אור מונוכרומטי, גששי אורך
364	A	P	Flatness, Parallels	מקבילים	Up to 50*100*400]	2 µm	DIN 6346 DIN 7151 DIN 7168	גששי אורך
365	A	P	Parallelism, Parallels	מקבילים	Up to 50*100*400]	2 µm	DIN 6346 DIN 7151 DIN 7168	גששי אורך
366	A	P	Perpendicularity,	ניצבות,	Up to 300 mm]	3.0 µm	DIN-875	גששי אורך

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities - Form, Angle					כיוול – גדלים מכניים - צורה, זווית		
367	A	P	Square, blade type	זוויתנים (300 mm to 600 mm]	5 µm	JIS B 7526	מד ניצבות
368	A	P		(600 mm to 900 mm]	8 µm		
369	A	P	Parallelism	מקבילות Up to 300 mm]	3 µm	DIN-875	גששי אורך
370	A	P	Square, blade type	זוויתנים (300 mm to 600 mm]	5 µm	JIS B 7526	
371	A	P		(600 mm to 900 mm]	8 µm		
372	A	P	Flatness,	מישוריות Up to 300 mm]	3 µm		
373	A	P	Square, blade type	זוויתנים (300 mm to 600 mm]	5 µm		
374	A	P		(600 mm to 900 mm]	8 µm		
375	A	P	Perpendicularity, Cylinder	גליל ניצבות Up to 600 mm]	2 µm	JIS B 7539	
376	A	P	Perpendicularity,	ניצבות Up to 100 mm]	3 µm	DIN 875	
377	A	P	Universal Box Angles	אביזר דפינה אוניברסאלי (100 mm to 300 mm]	5 µm	DIN 876	
378	A	P		(300 mm to 600 mm]	8 µm		
379	A	P	Flatness,	מישוריות Up to 100 mm]	3 µm	DIN 875	
380	A	P	Universal Box Angles	אביזר דפינה אוניברסאלי (100 mm to 300 mm]	5 µm	DIN 876	
381	A	P		(300 mm to 600 mm]	8 µm		
382	A	P	Parallelism	מקבילות Up to 100 mm]	3 µm	DIN 875	

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Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

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Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities - Form, Angle						כיוול – גדלים מכניים - צורה, זווית		
383	A	P	Universal Box Angles	אביזר דפינה אוניברסאלי	(100 mm to 300 mm]	5 µm	DIN 876	
384	A	P			(300 mm to 600 mm]	8 µm		
385	A	P	Squareness Right angle and box angle plate	ברך, קוביה	Up to 600 mm]	[3 + 1 per 100 mm] µm	WI-C050	מד ניצבות
386	A	P	Parallelism Right angle and box angle plate	ברך, קוביה	Up to 600 mm]	[1 + (1 per 100 mm)] µm	WI-C050	מד ניצבות
387	A	P	Perpendicularity Square master	מד ניצבות	600 mm	2.1 µm	נתוני יצרן WI-C018	השוואה למדיד אב לניצבות
388	A	P	Perpendicularity Vee blocks	פריזמות	Up to 150 mm]	2.1 µm	BS 3731 JIS B 7540	Grade 00 גששי אורך גליליים
389	A	P	Flatness, Vee blocks	פריזמות	Up to 150 mm]	2.1 µm	BS 3731 JIS B 7540	Grade 00 גששי אורך גליליים
390	A	P	Parallelism Vee blocks	פריזמות	Up to 150 mm]	2.1 µm	BS 3731 JIS B 7540	Grade 00 גששי אורך גליליים
391	A	P	Angle Sines bars and tables	זווית סרגלים ושולחנות סינוס	Up to 500 mm]	2 "	BS 3064 GGG-B 121b DIN 2273	Angle is estimated by measuring distance מקבילונים בלוק זוויתי
392	A	P	Angle Level	פלס	± 5 °	0.5 "	DIN 887 BS 958	1 µ/m sensitivity מייצר זוויות קטנות
393	A	P	Angle Clinometer	קלינומטר	Up to 90 °]	10 "	DIN 887 BS 958	מייצר זוויות קטנות

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח



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Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities - Form, Angle					כיוול – גדלים מכניים - צורה, זווית		
394	A	P	Angle Bevel protractor	מד זווית מתכוונן up to 360 °)	3 ´	BS 1685	בלוק זוויתי גששי אורך מד ניצבות
395	A	P;T	Rotational Speed Mechanical tachometer	מהירות סיבוב (סל"ד) מד סל"ד מכני	[1 to 5000] RPM 0.1 % OR or 0.2 RPM Whichever is greater	Manufacturer instructions WI-C069	Counter מונה
396	A	P;T	Rotational Speed Optical tachometer	מהירות סיבוב (סל"ד) מד סל"ד אופטי	[1 to 2500] RPM 0.02 % OR or 1 resolution Whichever is greater		Function generator מחולל אותות
397	A	P;T	Rotational Speed Optical tachometer	מהירות סיבוב (סל"ד) מד סל"ד אופטי	[2500 to 99999] RPM 0.005 % OR		Function generator מחולל אותות

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות
התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

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Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities - Hardness Meters					כיוול – גדלים מכניים - מדי קושיות		
398	A	P;T	Rockwell hardness testing machine	מכשירים למדידת קשיות בשיטת רוקוול	HRA [20 to 95]	0.45 HRA	ASTM E18 ISO 6508-2 Indirect verification השוואה לחומר יחוס סטנדרטי
399	A	P;T			HRBW [10 to 100]	0.7 HRBW	
400	A	P;T			HRC [10 to 70]	0.45 HRC	
401	A	P;T			HREW [70 to 100]	0.9 HREW	
402	A	P;T			HR15N [70 to 94]	0.5 HR15N	
403	A	P;T			HR30N [42 to 86]	0.5 HR30N	
404	A	P;T			HR45N [20 to 77]	0.5 HR45N	
405	A	P;T			HR15TW [67 to 93]	0.7 HR15TW	
406	A	P;T			HR30TW [29 to 82]	0.7 HR30TW	
407	A	P;T			HR45TW [10 to 72]	1.1 HR45TW	
408	A	P;T	Brinell hardness testing machine	מכשירים למדידת קשיות בשיטת ברינל	HBW 2.5 / 187.5	2% HBW	ASTM E10 Indirect verification השוואה לחומר יחוס סטנדרטי
409	A	P;T	Vickers hardness testing machine	מכשירים למדידת קשיות בשיטת וויקס	(0.1 to 0.5) HV	1.5% HV	ASTM E384 ISO 6507-2 Indirect verification השוואה לחומר יחוס סטנדרטי
410	A	P;T			(1 to 100) HV	1.2% HV	

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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The certificate attached is an integral part of the schedule and is numbered identically **התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח**

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities - Hardness Meters					ביול – גדלים מכניים - מדי קושיות		
			Shore hardness testing equipment (durometer)	מכשירים למדידת קשיות בשיטת שור	Type A Instruments	ASTM D2240 ISO 21509 ISO 18898	Direct verification ביול כח קפיץ ביחידות Shore Durocalibrator
411	A	P	SHORE A	שור A	[0 to 100] Shore	0.4 SHORE A	
412	A	P	Indenter extension	אורך החודרן	[0.1 to 2.54] mm	0.010 mm	בדיקת פרמטרים של החודרן
413	A	P	Indenter diameter	קוטר חוד החודרן	[0.76 to 0.82] mm	0.008 mm	Profile projector
414	A	P	Indenter angle	זווית החודרן	[34.75° to 35.25°]	0.05°	Microscope
415	A	P	Intender diameter	קוטר החודרן	[1.1 to 1.4] mm	0.03 mm	
416	A	P	Presser foot hole diameter	קוטר קדח הבסיס	[2.5 to 3.5] mm	0.03 mm	Indenter with parameters out of the nominal range may be calibrated at stated uncertainties as well
417	A	P	Presser foot diameter	קוטר בסיס לחיצה	[10 to 50] mm	0.05 mm	
					Type D Instruments		
418	A	P	SHORE D	שור D	[10 to 100] Shore	0.4 SHORE D	
419	A	P	Indenter extension	אורך החודרן	[0.1 to 2.54] mm	0.010 mm	
420	A	P	Indenter radius	רדיוס חוד החודרן	[0.088 to 0.112] mm	0.008 mm	
421	A	P	Indenter angle	זווית החודרן	[29° to 31°]	0.05°	
422	A	P	Intender diameter	קוטר החודרן	[1.1 to 1.4] mm	0.03 mm	
423	A	P	Presser foot hole diameter	קוטר קדח הבסיס	[2.5 to 3.5] mm	0.03 mm	
424	A	P	Presser foot diameter	קוטר בסיס לחיצה	[10 to 50] mm	0.05 mm	

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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The certificate attached is an integral part of the schedule and is numbered identically למספר הנספח

Schedule of Accreditation

The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities - Length						כיוול – גדלים מכניים - אורך		
439	A	P	Length, Length Gauges	אורך, מדידי אורך	Up to 1000 mm]	[0.1 + 2.5×length] µm	ISO 3650 DIN 861 ASME B89.1.13	Length bar Length in m
440	A	P	Length, Step Gauge	אורך, מקבילונים מדורגים	Up to 600 mm]	[0.1 + 2.5×length in m] µm	נתוני יצרן WI-C019	Length bar Length in m
441	A	P	Length Measuring Machine	מכונת מדידת אורך	Up to 500 mm	[0.1 + 2.5×length] µm	Manufacturer Instructions WI-C002 WI-C076	Length bar Length in m
442	A	P	Length, Plain Plug Gauges	אורך, מדידי תקע חלק	[1 to 25.4] mm	1 µm	ISO R/286 DIN 7162 DIN 7163 DIN 7164 H28/SEC.6 DIN 2269	מכונת מדידה SIP / TRIMOS 305M מיקרומטר שולחני
443	A	P			(25 mm to 100) mm	1.5 µm		
444	A	P	Diameter Plain Rings	טבעות חלקות	[2 mm to 100 mm]	0.4 µm	DIN 2250	מכונת מדידה SIP / TRIMOS 305M by comparison to gauge block in clamp calibration by comparison to standard plain ring provides lower uncertainties
445	A	P			(100 mm to 150 mm]	1.5 µm		
446	A	P			(150 mm to 205 mm]	2 µm		
447	A	P	Diameter Thread Measuring Cylinders	תיילים לבדיקת מדיד הברגה	[0.1 mm to 6 mm]	0.7 µm	H28/SEC.22A	מכונת מדידה SIP / TRIMOS 305M

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח



Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities - Length						כיוול – גדלים מכניים - אורך		
448	A	P	Pitch Diameter Screw Plug Gauges (parallel) including check and setting Plug	מדיד הברגה זכר – מקביל	Plug Diameter [1 mm to 100 mm]	3 μm	F-STD-H-28 ISO 228/1-2 ISO 1502 ISO 2903/4 ISO 7/1,29 BS 919/1,2,3 BS 849 BS 3409/1,2 BS 4377/2 BS 21 DIN 103/9 DIN 405 DIN 2999/4 B.N.A.e HELI-COIL WI-C020 WI-C023 WI-C024	כיוול זווית השן מדיד הברגה זכר קוני – ראה בטכנולוגיה כיוול – גדלים מכניים – צורה, זווית
449	A	P			(100 mm to 305 mm]	5 μm		
450	A	P	Pitch Screw Plug Gauges (parallel) including check and setting Plug	פסיעת התברג מדיד הברגה זכר מקביל	Plug Diameter [1 mm to 305 mm]	1.5 μm		
451	A	P	Pitch Diameter Screw Plug Gauges (taper)	מדיד הברגה זכר - קוני	Plug Diameter [1 mm to 100 mm]	3 μm		כיוול זווית השן מדיד הברגה זכר קוני – ראה בטכנולוגיה כיוול – גדלים מכניים – צורה, זווית
452	A	P			(100 mm to 305 mm]	5 μm		
453	A	P	Pitch Screw Plug Gauges (taper)	פסיעת התברג מדיד הברגה זכר קוני	Plug Diameter [1 mm to 305 mm]	1.5 μm		
454	A	P	Pitch Diameter Thread rings (parallel)	טבעות הברגה – מקבילה	Ring diameter [1.2 mm to 3 mm]	Not relevant	F-STD-H 28 ISO 228/1-2	Go no go test by means of check plug מכונת מדידה
455	A	P			(3 mm to 100 mm]	4 μm	ISO 1502	

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות
התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח



Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities - Length						כיוול – גדלים מכניים - אורך		
456	A	P			(100 mm to 305 mm]	5 µm	ISO 2903/2904 BS 919/1,23 BS 84 DIN 103/9 DIN 405 DIN 2999/2 B.N.A.e	SIP / TRIMOS 305M
457	A	P	Micrometer External	מיקרומטר חיצוני	Up to 2000 mm]	Heads 2.0 µm Setting and extension rods: [1 + 5×length in m] µm	ISO 3611 DIN 863 ASME B89.1.13 JIS B 7502	מקבילונים מוטות אורך
458	A	T			Up to 600 mm]	Heads 3.0 µm Setting and extension rods: [1 + 5×length in m] µm		
459	A	P	Micrometer Internal	מיקרומטר פנים	Up to 300 mm] extension rod to 1000 mm]	Heads 2.0 µm Setting and extension rods [1 + 5×length in m] µm	DIN 863 ASME B89.1.13	טבעות חלקות מכונת מדידה
460	A	P;T	Micrometer Depth	מיקרומטר עומק	Up to 250 mm]	Heads 2.0 µm Setting and extension rods [1 + 5×length in m] µm	DIN 863 ASME B89.1.13	מקבילונים
461	A	P	Micrometers (indicating digital and electronic)	מיקרומטר (כולל דיגיטלי)	Up to 2000 mm]	[1 + 5×length in m] µm Minimum 1.5 µm	ISO 3611 DIN 863 ASME B89.1.13 JIS B 7502	מקבילונים מוטות אורך
462	A	T			Up to 600 mm]	[1 + 5×length in m] µm Minimum 3.0 µm		
463	A	P	Three point Internal and bore micrometer	מיקרומטר פנים תלת נקודתי	[2 mm to 50 mm]	2 µm	DIN 863 Manufacturer Instructions WI-C012	טבעות חלקות
464	A	P			(50 mm to 150 mm]	5 µm		

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities - Length						כיוול – גדלים מכניים - אורך		
465	A	P	Micrometer head	ראש מיקרומטר	Up to 50 mm]	2 µm	Manufacturer;s instructions WI-C006	
466	A	P	Height setting micrometer	מד גובה מיקרומטרי	Up to 300 mm]	Heads 1.0 µm between any two points. Stepped column 2.5 µm Overall performance 3.0 µm	ISO 7863	מקבילונים, מוטות אורך
467	A	P	Riser Block	בסיס הגבהה למד גובה מיקרומטרי	Up to 150 mm]	2.5 µm	WI-C005	
468	A	P			(150 to 300 mm]	5 µm		
469	A	P;T	Vernier Caliper, depth Gauges	זחון ורנייר	Up to 2000 mm]	Overall performance [10 + 30× length in m] µm	DIN EN ISO 13385-1 DIN EN ISO 13385-2 DIN 862 -1988	מקבילונים, מוטות אורך, בודק זחונים
470	A	P;T	Caliper (digital and electronic)	זחון אלקטרוני ודיגיטלי	Up to 2000 mm]	Overall performance [10 + 30× length in m] µm	DIN EN ISO 13385-1 DIN EN ISO 13385-2 DIN 862 -1988	מקבילונים, מוטות אורך, בודק זחונים
471	A	P	Micrometer Heads Dial testers	מערכת כיוול חוגנים	Up to 25 mm	0.2 µm	WI-C028	Gauge blocks
472	A	P;T	Height Gauge Electronic microprocessor Controlled height Gauge	מד גובה	Up to 1000 mm]	[1 + 5× length in m] µm	BS 1643 JIS B 7517	
473	A	P;T	Dial Indicator	חוגן	Up to 3 mm]	0.3 µm	DIN 878 DIN 879	בודק חוגנים מכונת מדידה
474	A	P;T	Length gauge	גשש אורך	[3-60] mm	1 µm	JIS B 7509	

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The certificate attached is an integral part of the schedule and is numbered identically **התעודת המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח**



Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities - Length						כיול – גדלים מכניים - אורך		
475	A	P;T			[60-100] mm	1.5 µm	ANSI B89.1.10M NF E 11-056 ISO 13102	
476	A	P;T	Lever type dial indicator Lever type gauge	חוגן מנופי גשש מנופי	Up to 3 mm]	0.3 µm	BS 2795 PT.1 DIN 2270 MIL-I-18422D JIS B 7533 ISO 13102	בודק חוגנים
477	A	P;T	Thickness gauge	מד עובי	Up to 50 mm	2 µm	Manufacturer Instructions WI-C037	מקבילוני אורך Gauge blocks
478	A	P;T	Dial caliper gage (external type)	מד עובי זרועות	Up to 150 mm	10 µm	Manufacturer Instructions WI-C037	מקבילוני אורך Gauge blocks
479	A	P;T	Dial caliper gage (internal type)	מד חריצים	Up to 125 mm	10 µm	Manufacturer Instructions WI-C035	מיקרומטר, מקבילוני אורך Micrometer, Gauge blocks
480	A	P	Feeler Gauge	מד מרווח עלים	Up to 1 mm]	4 µm	DIN 2275	מיקרומטר
481	A	P;T	Measuring microscope	מיקרוסקופ מדידה	Up to 300 mm	[2 + (25/M)] µm	נתוני יצרן WI-C034	סרגל אופטי M is total magnification
482	A	P;T	Profile projectors	מטול פרופילרים	Up to 300 mm	[2 + (25/M)] µm	נתוני יצרן WI-C034	סרגל אופטי M is total magnification
483	A	P	Bore comparators (bore gauge)	מד קדח גשר	[6 mm to 150 mm]	2 µm	JIS B 7515 MIL-G-26762A MIL-G-26762A	בודק חוגנים טבעות חלקות מיקרומטר

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות
התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח



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Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities - Length					כיול – גדלים מכניים - אורך		
484	A	P	Bore comparators Cylinder gauge	פין מפציל [1 mm to 18 mm]	2 µm	נתוני יצרן WI-C011	
485	A	P	Optical scale	סרגל אופטי Up to 1 mm	0.5 µm	JIS B 7541 Manufacturer	מכונת מדידה TRIMOS/ SIP 305M
486				1 mm – 300 mm	1 µm	Instructions WI-C039	
487	A	P	Measuring rule	סרגל מדידה Up to 500] mm	20 µm	DIN 866, JIS-B 7516 Manufacturer	מיקרוסקופ מדידה כייל סרגלי וסרטי מדידה
488	A	P		(500 to 2000] mm	50 µm	Instructions WI-C078	Measuring microscope Scale and Tape Calibration Unit.
489	A	P	Measuring tape	סרט מדידה Up to 10] m	0.10 mm	OIML-R-35 Manufacturer	כייל סרגלי וסרטי מדידה
490				(10 to 50] m	0.40 mm	Instructions WI-C078	Scale and Tape Calibration Unit.
491	A	P;T	Length Length meter	אורך מד אורך [1 to 1000] m	0.01 m or 0.2 % OR Whichever is greater	WI-C069	Mechanical tachometer (Mode “m”) מונה מטרים
492	A	P;T	Surface Speed Surface Speed meter	מהירות פני השטח מד מהירות פני השטח [2 to 500] m/min	0.1 m/min or 0.2 % or Whichever is greater	WI-C069	Mechanical tachometer (Mode “m/min”) מד מהירות
493		P	Test sieves	נפות Nominal aperture size : Up to 0.2 mm	0.003 mm	ASTM E11 ISO 3310 BS 410	מטול פרופילר, זחון Profile projector, caliper.
494	A	P		0.2 mm – 1 mm	0.005 mm		
495	A	P		1 mm – 5 mm	0.010 mm		

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות
התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח



Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities - Length						כיוול – גדלים מכניים - אורך		
496	A	P			5 mm – 15 mm	0.020 mm		
497	A	P			15 mm – 30 mm	0.050 mm		
498	A	P			Above 30 mm	0.10 mm		
499	A	P:T	Extensometer	מד התארכות	[0.01 mm to 50 mm]	0.004 mm	ASTM E83 ISO 9513 ISO 5893	Extensometer calibrator
500	A	P:T	Extensometer (displacement)	מד התארכות	[0.01 mm to 1000 mm]	0.006 mm	Manufacturer Instructions WI-C075	High precision dial gauge, Length gauge
501	A	P;T	Length measurements	מדידת אורך	Up to 125 mm]	0.003 mm	Customer requirements WI-C081	
502	A	P;T			(125 mm to 200 mm]	0.005 mm		
503	A	P;T			(200 mm to 600 mm]	0.007 mm		
504	A	P;T			(600 mm to 2000 mm]	0.05 mm		

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The certificate attached is an integral part of the schedule and is numbered identically. הנספח הנספח הזה למספר הנספח הזה ומספרה זהה להקבלתו. התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח הזה.



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Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Physical Quantities - Optics					כיוול – גדלים פיזיקליים - אופטיקה		
505	A	P,T	Optical emitting devices and Meters מכשיר פולט קרינה אופטית ומד קרינה אופטית	Power 3 n.W to 3 m.w at 270 to 950 nm and 15μW to 150 W at 193 nm to 10600 nm הספק	3.5% of Reading	In house procedure Based on: IEC 60825 ISO 13694 WI-C203	
506	A	P,T	Light emitting devices and Meters מכשיר פולט אור ומד קרינה אופטית	Energy 20μJ to 4 KJ at 193 to 10600 nm	5% of Reading	In house procedure Based on: IEC 60825 ISO 13694 WI-C203	
507	A	P,T	Optical emitting devices and Meters מכשיר פולט קרינה אופטית ומד קרינה אופטית	Frequency & Time תדר וזמן Up to 0.7 MHz Min. Rise/Fall Time 2 nsec	1 nsec	In house procedure Based on: IEC 60825 ISO 13694 WI-C202	
508	A	P,T	Light Meters מד קרינה אופטית	Wavelength 25 nm to 3507 nm	2x10-4 nm	In house procedure Based on: IEC 60825 ISO 13694 WI-C200	NIST Atomic Spectra Database
509	A	P,T	Optical emitting devices and Meters מכשיר פולט קרינה אופטית ומד קרינה אופטית	Wavelength אורך גל 200 nm to 1100 nm	1 nm	In house procedure Based on: IEC 60825 ISO 13694 WI-C200	
510	A	P,T	Light emitting devices and Meters מכשיר פולט אור ומד אור	Light אור 0 to 2.0E+5 lux	0.5 res or 5.0 % Whichever is greater	In house procedure The CIE 1924 photopic V(λ) luminosity function WI-C201	
511	A	P,T	Light emitting devices and Meters מכשיר פולט אור ומד אור	Visible light 6.85*10-3 cd/m2 to 3120 cd/m2	5% of Reading		Calibration can be given in other units as required.

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

Flexible scope in analytical tests: Type of matrix, analytes, experimental systems and/or analytical characteristics may be subject to changes, in accordance with the laboratory's approved and documented procedures. For details, please refer to the list of Accredited Tests, available from the laboratory upon request.

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות זהה למספר הנספח והוא חלק בלתי נפרד ממנו ומספר זה מהווה חלק בלתי נפרד מהסמכת מעבדות

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Physical Quantities - Force, Torque						כיוול – גדלים פיזיקליים - כח, מומנט		
512	A	P,T	Force calibration in tension, force measurement machine	כיוול כח במתיחה, מכונות למדידת כח	[0.1 kN to 100 kN]	1.5 N/kN of verification force	ISO 7500-1 ASTM E4 Manufacturer instructions WI-C056	מתמר כח Force load cell Calibration can be given in other units as required. 1 N/kN = 0.1%
513	A	T	Force calibration in tension, material testing machine	כיוול כח במתיחה, מכונות למדידת כח	[0.1 kN to 500 kN]	2.0 N/kN of verification force		
514	A	P;T	Force calibration in compression, material testing machine	כיוול כח בלחיצה, מכונות למדידת כח	[0.1 kN to 1 MN]	2.0 N/kN of verification force		כיוול כיוול מכונות בדיקה לפי דרישות תקן ישראלי 26 חלק 4.1
515	A	P;T			(1 MN to 2.3 MN)	2.4 N/kN of verification force		
516	A	P;T	Force calibration in tension and compression, push pull force measurement machine	כיוול כח בלחיצה ומתיחה מכונות למדידת כוח	(0.005 N to 1.2 kN)	1.0 N/kN of verification force		משקולות
517	A	P	Force calibration in tension and compression, Proving devices	כיוול כח בלחיצה ומתיחה תאי (טבעות) כוח	[0.005 N to 1.2 kN]	0.5 N/kN of verification force	ISO 376 Euramet cg-4	משקולות, מתמר כח
518	A	P			[1 kN to 20 kN]	0.7 N/kN of verification force		
519	A	P	Force calibration in compression, Proving devices	כיוול כח בלחיצה תאי (טבעות) כוח	[20 kN to 1 MN]	1.0 N/kN of verification force		
520	A	P			[1 MN to 2.3 MN]	2.0 N/kN of verification force		
521	A	P	Force calibration in tension, Proving devices	כיוול כח במתיחה תאי (טבעות) כוח	[20 kN to 100 kN]	1.0 N/kN of verification force		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

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Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Physical Quantities - Force, Torque						כיוול – גדלים פיזיקליים - כח, מומנט		
522	A	P	Torque	מומנט	[0.01 Nm to 1000 Nm]	0.5 % OR	ISO 6789	מתמרי מומנט
523	A	P	Torque wrenches and drivers	ידית מומנט, מברגת מומנט				Calibration can be given in other units as required OR – Of Reading
524	A	P	Torque	מומנט	[0.001 Nm to 0.01 Nm]	0.25 % OR	BS 7882 Euramet cg-14 Manufacturer's instructions WI-C061	OR – Of Reading
525	A	P	Mechanical and Electronic torque calibration equipment	מכשירים למדידת מומנט (מכאניים ואלקטרוניים)	[0.01 Nm to 1000 Nm]	0.1 % OR		קורות כיוול ומשקולות
526	A	T	Torque Mechanical and Electronic torque calibration equipment	מומנט מכשירים למדידת מומנט (מכאניים ואלקטרוניים)	[0.1 Nm to 50 Nm]	0.2 % OR		קורות כיוול ומשקולות
527	A	T	Torque Mechanical and Electronic torque calibration equipment	מומנט מכשירים למדידת מומנט (מכאניים ואלקטרוניים)	(50 Nm to 1000 Nm]	1 % OR		מתמרי מומנט OR – Of Reading

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

Flexible scope in analytical tests: Type of matrix, analytes, experimental systems and/or analytical characteristics may be subject to changes, in accordance with the laboratory's approved and documented procedures. For details, please refer to the list of Accredited Tests, available from the laboratory upon request.

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Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

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Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks		
Calibration – Physical Quantities - Humidity						כיוול – גדלים פיזיקליים - לחות				
528	A	P	Relative humidity	לחות יחסית	0 °C to 10 °C	1.0 % rh	ASTM-E-104-85 NIS 19 OIML R121 Manufacturer instructions WI-C046	Chilled mirror hygrometer. היגרומטר מד נקודת טל. Humidity and temperature controlled chamber. תא מבוקר לחות וטמפרטורה.		
529	A	P	RH meters		(5% rh to 50%] rh				1.4 % rh	
			RH data loggers		(50% rh 80%] rh					
			RH probes							
			RH transducers	לחות יחסית מדי לחות רגשי לחות מתמרי לחות אוגרי נתונים	10 °C to 45 °C	0.8 % rh				
530	A	P	לחות יחסית						(5% rh to 50%] rh	1.1 % rh
531	A	P	מדי לחות						(50% rh 80%] rh	1.3 % rh
532	A	P	רגשי לחות						(80% rh 95%] rh	
533	A	P		לחות יחסית	45 °C to 60 °C	0.8 % rh				
534	A	P			(5% rh to 50%] rh	1.0 % rh				
				לחות יחסית	0 °C to 10 °C	2.0 % rh		Humidity sensors, Humidity and temperature controlled Calibrator		
535	A	T	Relative humidity						[5% rh to 80%] rh	
			RH probes							
536	A	T	RH chambers						10 °C to 45 °C	2.0 % rh
			RH meters	[5% rh to 95%] rh						
537			לחות יחסית רגשי לחות תאי לחת מדי לחות	לחות יחסית	45 °C to 60 °C	2.0 % rh				
538	A	T			[5% rh to 80%] rh					

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

Flexible scope in analytical tests: Type of matrix, analytes, experimental systems and/or analytical characteristics may be subject to changes, in accordance with the laboratory's approved and documented procedures. For details, please refer to the list of Accredited Tests, available from the laboratory upon request.

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The certificate attached is an integral part of the schedule and is numbered identically **התעודת המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח**

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Physical Quantities - Humidity					כיוול – גדלים פיזיקליים - לחות		
539	A	P;T	Relative humidity RH probes	23°C ± 2 °C	0.5% rh		Salt solutions in ampoules as humidity standards.
540	A	P;T	לחות יחסית	11.3% rh	0.7% rh		
541	A	P;T	לחות יחסית	35% rh	1.1% rh		
542	A	P;T	רגשי לחות	50% rh	1.5% rh		
543	A	P;T		75% rh	1.5% rh		
544	A	P;T		80% rh	1.6% rh		
545	A	P;T	Dew point	[- 40 °C to - 30] °C	0.35 °C		Chilled mirror hygrometer היגרומטר מד נקודת טל.
546	A	P;T	RH meters	[- 30 °C to + 50] °C	0.2 °C		
547	A	P;T	RH transducers	(50 °C to 60] °C	0.25 °C		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

Flexible scope in analytical tests: Type of matrix, analytes, experimental systems and/or analytical characteristics may be subject to changes, in accordance with the laboratory's approved and documented procedures. For details, please refer to the list of Accredited Tests, available from the laboratory upon request.

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח



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Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Physical Quantities - Mass						כיוול – גדלים פיזיקליים - מסה		
	A	P	Mass	מסה	20000 g	40 mg	OIML R 111-1	מאזני השוואה
	A	P	Weights	משקולות	10000 g	5.1 mg	OIML R 52	Calibration can be given in other units as required.
	A	P			5000 g	2.9 mg	ASTM-E-617	Intermediate value can be calibrated with an uncertainty interpolated from the next higher and lower values in the table.
	A	P			2000 g	0.63 mg		
	A	P			1000 g	0.50 mg		
	A	P			500 g	0.35 mg		
	A	P			200 g	0.080 mg		
	A	P			100 g	0.049 mg		
	A	P			50 g	0.030 mg		
	A	P			20 g	0.021 mg		
	A	P			10 g	0.020 mg		
	A	P			5 g	0.0081 mg		
	A	P			2 g	0.0063 mg		
	A	P			1 g	0.0054 mg		
	A	P			0.5 g	0.0044 mg		
	A	P			0.2 g	0.0035 mg		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

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Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Physical Quantities - Mass						כיוול – גדלים פיזיקליים - מסה		
5	A	P			0.1 g	0.0029 mg		מאזני השוואה
	A	P			0.05 g	0.0026 mg		
	A	P			0.02 g	0.0025 mg		
	A	P			0.01 g	0.0020 mg		
	A	P			0.005 g	0.0020 mg		
	A	P			0.002 g	0.0020 mg		
	A	P			0.001 g	0.0020 mg		
	A	P			[0.5 g to 200 g]	0.1 mg		
	A	P			(200 g to 1 kg]	0.5 mg		
	A	P			(1 kg to 5 kg]	20 mg		
	A	P			(5 kg to 10 kg]	30 mg		
	A	P			(10 kg to 29 kg]	60 mg		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

<i>Item</i>	<i>Scope Type</i>	<i>Site</i>	<i>Measurand Instrument, Gauge</i>	<i>Range [Including margins] (Does not include margins)</i>	<i>CMC Expressed as an Expanded Uncertainty (95%)</i>	<i>Reference Documents</i>	<i>Remarks</i>
Calibration – Physical Quantities - Mass						כיוול – גדלים פיזיקליים - מסה	
§ A	P;T		Non automatic weighing instruments	מאזניים לא אוטומטיים (Up to 10 mg]	2.5 µg	OIML R76	1. Uncertainties depend on the performance of the weighting machine under calibration. 2. Available weights are: OIML Class E2 from 1 mg to 2 kg, OIML Class F1 from 1 mg to 5 kg, OIML Class F2 from 1 mg to 5 kg, OIML Class M1 from 1 mg to 20 kg, OIML Class M2 from 5 kg to 20 kg, test weights 2 × 500 kg. OIML Class E1weights can be provided on demand.
§ A	P;T		Resolution 0.001 mg and less	כושר הפרדה 0.001 mg או נמוך. (10 mg to 500 mg]	5 µg	Manufacturer instructions	
§ A	P;T			(500 mg to 2 g]	7 µg	WI-C044	
§ A	P;T			(2 g to 5 g]	10 µg		
§ A	P;T			(5 g to 20 g]	25 µg		
§ A	P;T			(20 g to 50 g]	30 µg		
§ A	P;T		Non automatic weighing instruments	מאזניים לא אוטומטיים (Up to 5 g]	15 µg		
§ A	P;T		Resolution 0.01 mg	כושר הפרדה, 0.01 mg (5 g to 50 g]	40 µg		
§ A	P;T			(50 g to 250 g]	80 µg		
§ A	P;T		Non automatic weighing instruments	מאזניים לא אוטומטיים (Up to 50 g]	0.1 mg		
§ A	P;T		Resolution 0.1 mg	כושר הפרדה 0.1 mg (50 g to 250 g]	0.2 mg		
§ A	P;T			(250 g to 520 g]	0.4 mg		
§ A	P;T		Non automatic weighing instruments	מאזניים לא אוטומטיים (Up to 620 g]	2 mg		
§ A	P;T		Resolution 0.001 g	כושר הפרדה 0.001 g (620 g – 2 kg]	3 mg		
§ A	P;T		Non automatic weighing instruments	מאזניים (Up – 5.1 kg]	0.01 g		
§ A	P;T		Resolution 0.01 g	כושר הפרדה, 0.01 g (5.1 kg – 12.1 kg]	0.02 g		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Physical Quantities - Mass						כיוול – גדלים פיזיקליים - מסה		
5	A	P;T	Non automatic weighing instruments	מאזניים לא אוטומטיים	(0 to 8.1 kg]	0.1 g		
5	A	P;T	Resolution 0.1 g	כושר הפרדה 0.1 g	(8.1 kg to 32 kg]	0.2 g		
5	A	P;T			(32 kg to 64 kg]	0.4 g		
5	A	P;T	Non automatic weighing instruments	מאזניים לא אוטומטיים	(Up to 50 kg]	1 g		
5	A	P;T	Resolution 0.001 kg	כושר הפרדה 0.001 kg	(50 kg to 150 kg]	2 g		
5	A	P;T	Non automatic weighing instruments	מאזניים לא אוטומטיים	(Up to 200 kg]	10 g		
5	A	P;T	Resolution 0.01 kg	כושר הפרדה 0.01 kg	(200 kg to 500 kg]	20 g		
5	A	P;T	Non automatic weighing instruments	מאזניים לא אוטומטיים	(Up 0 to 1000 kg]	0.1 kg		
6	A	P;T	Resolution 0.1 kg	כושר הפרדה 0.1 kg	(1000 kg to 2000 kg]	0.2 kg		
6	A	P;T	Non automatic weighing instruments	מאזניים לא אוטומטיים	(Up to 10000 kg]	0.5 kg		
			Resolution 0.5 kg	כושר הפרדה 0.5 kg				

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

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Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Physical Quantities - Pressure						כיוול - גדלים פיזיקליים – לחץ		
607	A	P	Hydraulic pressure, Dead weight tester. Effective area of hydraulic dead weight tester piston	לחץ הידראולי כיוול שטח אפקטיבי של בוכנת מאזני לחץ הידראוליים	[0.6 MPa to 121 MPa]	0.20 Pa/kPa	Euramet cg 3 Manufacturer instructions WI-C068	DH-Budenberg 580HX Dead weight tester to be supplied with its mass set Calibration by means of cross float method
608	A	T	Pneumatic pressure Absolute Pressure indicating instruments and gauges	לחץ פניאומאטי, אבסולוטי מדידי לחץ פניאומאטיים	[1.6 kPa to 0.7 MPa]	1.5 Pa/kPa	OIML-R 101 Euramet cg 17 BHS-IP2 ISO 81060-2	Druck 610 Druck 603 Druck 104 CONTEC MS200
609	A	T	Pneumatic pressure Gauge Pressure indicating instruments and gauges	לחץ פניאומאטי, יחסי מדידי לחץ פניאומאטיים	[1.6 kPa to 7 MPa]	1.0 Pa/kPa	Manufacturer instructions WI-C047	
610	A	T	Hydraulic pressure (gauge) Pressure indicating instruments and gauges	לחץ הידראולי מדידי לחץ	[0.6 MPa to 70 MPa]	1.0 Pa/kPa		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח



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Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Physical Quantities - Temperature						כיוול – גדלים פיזיקליים - טמפרטורה		
611	A	P	Liquid in glass thermometers	תרמומטרים נוזל בזכוכית	[- 80 °C to – 30 °C]	0.15 °C	ISO 1770	אמבטיות כיוול
612	A	P			(- 30 °C to 0 °C]	0.1 °C	ISO 1771	תרמומטר אב PRT
613	A	P			0 °C	0.01 °C	ISO 386	
614	A	P			(0 °C to 250 °C]	0.08 °C	JIS 7411	
615	A	P			(250 °C to 550 °C]	0.5°C	JIS 7412	
616	A	T			[-40 °C to 150 °C]	1.0 °C	JIS 7542	
617	A	T			0 °C	0.05 °C	ASTM E563	
618	A	T			(150 °C to 250 °C]	2.0 °C	ASTM E77	
619	A	P	PRT	גששי טמפרטורה התנגדות	-196 °C	0.02 °C	BS 593	Liquid nitrogen
620	A	P	Measurement by comparison		[- 90 °C to -80 °C)	0. 2 °C	ASTM-E-1137	PRT may calibrated with its indicator. The uncertainty will be dependent on the indicator performance.
621	A	P			[- 80 °C to 250 °C]	0.02 °C	ASTM-E-644	
622	A	P			(250 °C to 550 °C]	0.05 °C	IEC 751	
623	A	P			(550 °C to 661 °C]	0.3 °C	ITS-90	
624	A	P			0.01 °C	0.006 °C	Manufacturer instructions WI-C065	
625	A	T	PRT	גששי טמפרטורה התנגדות	-196 °C	0.1 °C	Manufacturer instructions WI-C065	Liquid nitrogen
626	A	T	Measurement by comparison		[- 90 °C to – 40 °C]	0.3 °C		
627	A	T			[- 40 °C to 140 °C]	0.1 °C		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Physical Quantities - Temperature						כיוול – גדלים פיזיקליים - טמפרטורה		
628	A	T			(140 °C to 250 °C]	0.3 °C		
629	A	T			(250 °C to 650 °C]	0.5 °C		
630	A	P	TC base metal	צמדים תרמיים מתכות בסיסיות	-196 °C	0.14 °C	ASTM-E-230	Liquid nitrogen
631	A	P	Measurement by comparison		[- 90 °C to -80 °C)	0.2 °C	ASTM-E-220 ITS-90	TC may calibrated with its indicator. The uncertainty will be dependent on the indicator performance.
632	A	P			[- 80 °C to 250 °C]	0.14 °C	Manufacturer instructions	
633	A	P			(250 °C to 550 °C]	0.4 °C	WI-C065	
634	A	P			(550 °C to 1100 °C]	1 °C		
635	A	T			-196 °C	0.3 °C		
636	A	T			[- 80 °C to -40 °C]	0.5 °C		
637	A	T			[- 40 °C to 250 °C]	0.3 °C		
638	A	T			(250 °C to 550 °C]	0.5 °C		
639	A	T			(550 °C to 1100 °C]	1.5 °C		
640	A	P	TC noble metal	צמדים תרמיים מתכות אצילות	[- 50 °C to 550 °C]	0.4 °C	ASTM-E-230	TC may calibrated with its indicator. The uncertainty will be dependent on the indicator performance.
641	A	P	Measurement by comparison		(550 °C to 1100 °C]	1 °C	ASTM-E-220	
642	A	T			[- 50 °C to 250 °C]	0.5 °C	ITS-90	
643	A	T			(250 °C to 550 °C]	0.7 °C	Manufacturer instructions	
644	A	T			(550 °C to 1100 °C]	1.5 °C	WI-C065	
645	A	P;T	Freezing chambers Including uniformity	מקפיאים כולל בדיקת אחידות	[-90 °C to –50 °C]	1 °C	DKD-R-5-7 Manufacturer instructions WI-C062	TC, PRT, Data logger

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The certificate attached is an integral part of the schedule and is numbered identically למספר הנספח



Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Physical Quantities - Temperature					כיוול – גדלים פיזיקליים - טמפרטורה		
646	A	P;T	Freezers, Incubators, Autoclaves Including uniformity	מקפאים, אינקובטורים אוטוקלבים כולל בדיקת אחידות [-50 °C to 151 °C]	0.5 °C	DKD-R-5-7 DIN 12880 Manufacturer instructions WI-C062	TC, PRT, Data logger
647	A	P;T	Furnaces Including uniformity	תנורים כולל בדיקת אחידות [50 °C to 300 °C]	0.7 °C	DKD-R-5-7 DIN 12880 Manufacturer instructions WI-C062	TC, PRT, Data logger
648	A	P;T		(300 °C to 550 °C)	1 °C		
649	A	P;T		(550 °C to 1100 °C)	2.5 °C		
650	A	P;T	Bathes Including uniformity	אמבט כולל בדיקת אחידות [-196 °C to 251 °C]	0.03 °C	Manufacturer instructions WI-C062	SPRT, PRT
651	A	P;T		(251 °C to 550 °C)	0.09 °C		
652	A	P	Dry block calibrator	תנור בלוק יבש [-110 °C to 300 °C]	0.05 °C	EURAMET cg-13 Manufacturer instructions WI-C062	PRT
653	A	P		(300 °C to 650 °C)	0.3 °C		
654	A	P;T	Tube furnace Including uniformity	תנור כיוול צינורי כולל בדיקת אחידות [300 °C to 660 °C]	0.2 °C	Manufacturer instructions WI-C062	
655	A	P;T		(660 °C to 1100 °C)	1.2 °C		
656	A	P;T	Temperature indicators, controllers, recorders and simulators for the resistance sensors	מד, רשמי ומדמי טמפרטורה עבור מדי התנגדות -200 °C to 800 °C	0.01 °C	EURAMET cg-11 Manufacturer instructions WI-C067	Calibration by means of electrical calibration,
657	A	P	Temperature indicators, controllers, recorders and simulators for the base metal thermocouples	מד, רשמי ומדמי טמפרטורה עבור צמודים תרמיים מתכות בסיסיות -200 °C to 1380 °C	0.2 °C	EURAMET cg-11 Manufacturer instructions WI-C067	Calibration by means of electrical calibration, including cold junction compensation
658	A	T		-200 °C to 1380 °C	0.4 °C		

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות



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Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Physical Quantities - Temperature						כיוול – גדלים פיזיקליים - טמפרטורה		
659	A	P	Temperature indicators, controllers, recorders and simulators for the noble metal thermocouples	מדוי, רשמי ומדמי טמפרטורה עבור צמדנים תרמיים מתכות אצילות	0 °C to 500 °C	0.5 °C	EURAMET cg-11 Manufacturer instructions WI-C067	Calibration by means of electrical calibration, including cold junction compensation
660	A	P			500 °C to 1800 °C	0.3 °C		
661	A	T			0 °C to 500 °C	0.9 °C		
662	A	T			500 °C to 1800 °C	0.6 °C		
663	A	P	Temperature, Infrared Thermometers,	טמפרטורה מדוי טמפרטורת קרינה	[35 °C to 100 °C]	0.6 °C	ASTM E2847 Manufacturer instructions WI-C080	IR Calibrator
664	A	P			(100 °C to 200 °C]	1.0 °C		
665	A	P			(200 °C to 350 °C]	1.7 °C		
666	A	P			(350 °C to 500 °C]	2.5 °C		

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות

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Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Small (up to 2L) Volume Volumetric Instruments					כיוול – כיוול מכשירים וולומטריים – נפחים קטנים עד 2 ליטר		
667 A	P		Liquid volume, Piston-operated volumetric apparatus	נפח נוזלים כיוול מכשירים וולומטריים בהנע בוכנה Nominal value 1µl	0.030 µl	ISO 8655- Part 1,2,3,4,5,6 ISO/TR 20461 Manufacturer instructions WI-C074	מתקן נפח מופעל בוכנה Intermediate volumes may be calibrated with uncertainty as for the higher volume value
668 A	P			2 µl	0.040 µl		
669 A	P			5 µl	0.050 µl		
670 A	P			10 µl	0.060 µl		
671 A	P			20 µl	0.080 µl		
672 A	P			50 µl	0.21 µl		
673 A	P			100 µl	0.27 µl		
674 A	P			200 µl	0.72 µl		
675 A	P			500 µl	1.3 µl		
676 A	P			1000 µl	1.8 µl		
677 A	P			2000 µl	5.4 µl		
678 A	P			5000 µl	9.6 µl		
679 A	P			10000 µl	15 µl		
680 A	P			20000 µl	20 µl		
681 A	P			25000 µl	25 µl		
682 A	P			50000 µl	35 µl		

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח